

SN54AHCT132, SN74AHCT132 QUADRUPLE POSITIVE-NAND GATES WITH SCHMITT-TRIGGER INPUTS

SCLS366 – MAY 1997

- Inputs Are TTL-Voltage Compatible
- **EPIC™** (Enhanced-Performance Implanted CMOS) Process
- Operation From Very Slow Input Transitions
- Temperature-Compensated Threshold Levels
- High Noise Immunity
- Same Pinouts as 'AHCT00
- Package Options Include Plastic Small-Outline (D), Shrink Small-Outline (DB), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

Each circuit functions as a NAND gate, but because of the Schmitt action, it has different input threshold levels for positive- and negative-going signals. The 'AHCT132 perform the Boolean function $Y = \overline{A \bullet B}$ or $Y = \overline{A} + \overline{B}$ in positive logic.

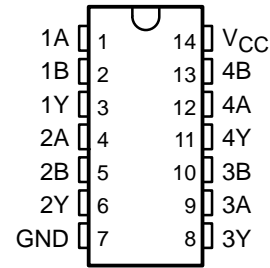
These circuits are temperature compensated and can be triggered from the slowest of input ramps and still give clean jitter-free output signals.

The SN54AHCT132 is characterized for operation over the full military temperature range of -55°C to 125°C . The SN74AHCT132 is characterized for operation from -40°C to 85°C .

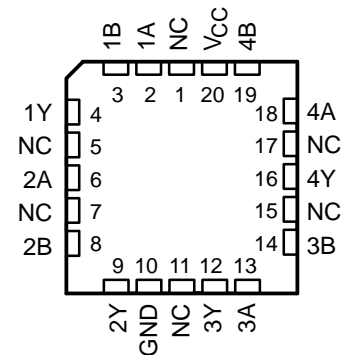
FUNCTION TABLE
(each gate)

INPUTS		OUTPUT
A	B	Y
H	H	L
L	X	H
X	L	H

SN54AHCT132 . . . J OR W PACKAGE
SN74AHCT132 . . . D, DB, N, OR PW PACKAGE
(TOP VIEW)



SN54AHCT132 . . . FK PACKAGE
(TOP VIEW)



NC – No internal connection



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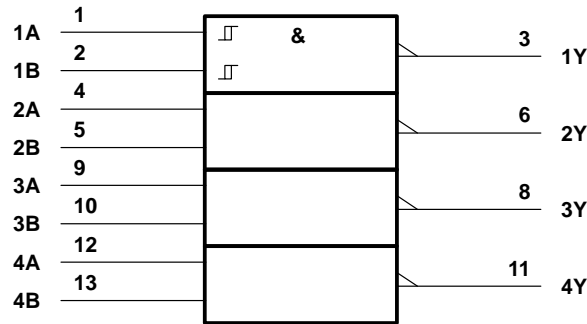
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PRODUCT PREVIEW

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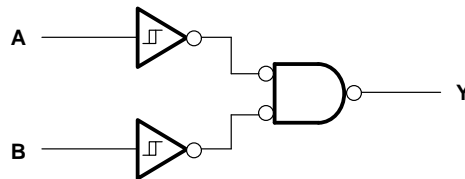
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logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.
Pin numbers shown are for the D, DB, J, N, PW, and W packages.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range‡

Supply voltage range, V_{CC}	–0.5 V to 7 V
Input voltage range, V_I (see Note 1)	–0.5 V to 7 V
Output voltage range, V_O (see Note 1)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	±20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±25 mA
Continuous current through V_{CC} or GND	±50 mA
Package thermal impedance, θ_{JA} (see Note 2): D package	127°C/W
DB package	158°C/W
N package	78°C/W
PW package	170°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

‡ Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

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recommended operating conditions (see Note 3)

		SN54AHCT132		SN74AHCT132		UNIT
		MIN	MAX	MIN	MAX	
V_{CC}	Supply voltage	4.5	5.5	4.5	5.5	V
V_{IH}	High-level input voltage	2		2		V
V_{IL}	Low-level input voltage		0.8		0.8	V
V_I	Input voltage	0	5.5	0	5.5	V
V_O	Output voltage	0	V_{CC}	0	V_{CC}	V
I_{OH}	High-level output current		–8		–8	mA
I_{OL}	Low-level output current		8		8	mA
T_A	Operating free-air temperature	–55	125	–40	85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V_{CC}	$T_A = 25^\circ\text{C}$			SN54AHCT132		SN74AHCT132		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
V_{T+} Positive-going input threshold voltage		4.5 V			1.9		1.9		1.9	V
		5.5 V			2.1		2.1		2.1	
V_{T-} Negative-going input threshold voltage		4.5 V	0.5			0.5		0.5		V
		5.5 V	0.6			0.6		0.6		
ΔV_T Hysteresis ($V_{T+} - V_{T-}$)		4.5 V	0.4		1.4	0.4	1.4	0.4	1.4	V
		5.5 V	0.4		1.5	0.4	1.5	0.4	1.5	
V_{OH}	$I_{OH} = -50\ \mu\text{A}$	4.5 V	4.4	4.5		4.4		4.4		V
	$I_{OH} = -8\ \text{mA}$		3.94			3.8		3.8		
V_{OL}	$I_{OL} = 50\ \mu\text{A}$	4.5 V			0.1		0.1		0.1	V
	$I_{OL} = 8\ \text{mA}$				0.36		0.5		0.44	
I_I	$V_I = V_{CC}$ or GND	5.5 V			± 0.1		± 1		± 1	μA
I_{CC}	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			2		20		20	μA
ΔI_{CC}^\dagger	One input at 3.4 V, Other inputs at V_{CC} or GND	5.5 V			1.35		1.5		1.5	mA
C_i	$V_I = V_{CC}$ or GND	5 V		2	10				10	pF

† This is the increase in supply current for each input at one of the specified TTL voltage levels rather than 0 V or V_{CC} .

switching characteristics over recommended operating free-air temperature range, $V_{CC} = 5\ \text{V} \pm 0.5\ \text{V}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	LOAD CAPACITANCE	SN54AHCT132				UNIT	
				T _A = 25°C			MIN		MAX
				MIN	TYP	MAX			
t _{PLH} *	A or B	Y	C _L = 15 pF	5	6.9	1	8	ns	
t _{PHL} *				5	6.9	1	8		
t _{PLH}	A or B	Y	C _L = 50 pF	5.5	7.9	1	9	ns	
t _{PHL}				5.5	7.9	1	9		

* On products compliant to MIL-PRF-38535, this parameter is ensured but not production tested.



SN54AHCT132, SN74AHCT132

QUADRUPLE POSITIVE-NAND GATES

WITH SCHMITT-TRIGGER INPUTS

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switching characteristics over recommended operating free-air temperature range,
 $V_{CC} = 5\text{ V} \pm 0.5\text{ V}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	LOAD CAPACITANCE	SN74AHCT132					UNIT
				T _A = 25°C			MIN	MAX	
				MIN	TYP	MAX			
t _{PLH}	A or B	Y	C _L = 15 pF	5	6.9	1	8	ns	
t _{PHL}				5	6.9	1	8		
t _{PLH}	A or B	Y	C _L = 50 pF	5.5	7.9	1	9	ns	
t _{PHL}				5.5	7.9	1	9		

noise characteristics, $V_{CC} = 5\text{ V}$, $C_L = 50\text{ pF}$, $T_A = 25^\circ\text{C}$ (see Note 4)

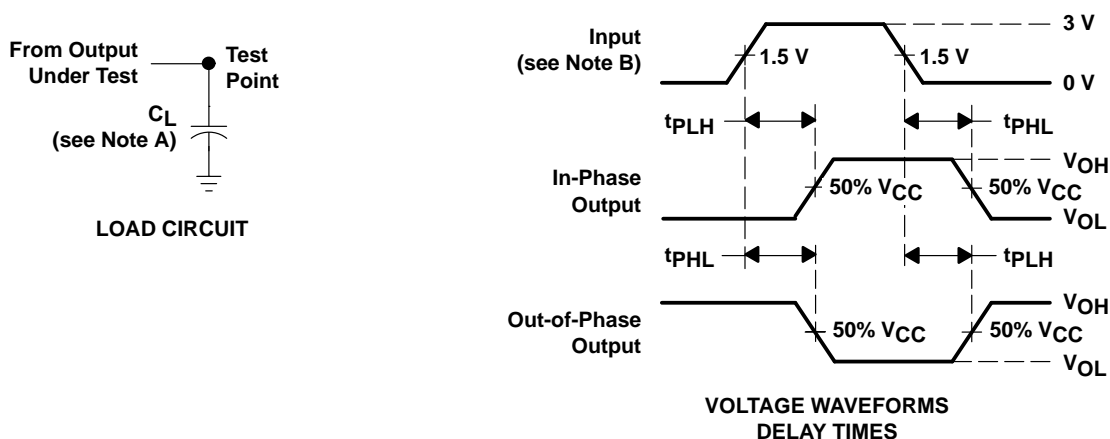
PARAMETER		SN74AHCT132			UNIT
		MIN	TYP	MAX	
$V_{OL(P)}$	Quiet output, maximum dynamic V_{OL}		0.4	0.8	V
$V_{OL(V)}$	Quiet output, minimum dynamic V_{OL}		-0.4	-0.8	V
$V_{OH(V)}$	Quiet output, minimum dynamic V_{OH}		4.5		V
$V_{IH(D)}$	High-level dynamic input voltage		2		V
$V_{IL(D)}$	Low-level dynamic input voltage			0.8	V

NOTE 4: Characteristics are determined during product characterization and ensured by design for surface-mount packages only.

operating characteristics, $V_{CC} = 5\text{ V}$, $T_A = 25^\circ\text{C}$

PARAMETER	TEST CONDITIONS	TYP	UNIT
C_{pd} Power dissipation capacitance	No load, $f = 1\text{ MHz}$		pF

PARAMETER MEASUREMENT INFORMATION



- NOTES: A. C_L includes probe and jig capacitance.
 B. Input pulses are supplied by generators having the following characteristics: $PRR \leq 1\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r = 3\text{ ns}$, $t_f = 3\text{ ns}$.
 C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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